

Supporting Information

Changes in near-bandgap photoluminescence in lead halide CsPbBr₃ perovskite, subjected to extreme conditions

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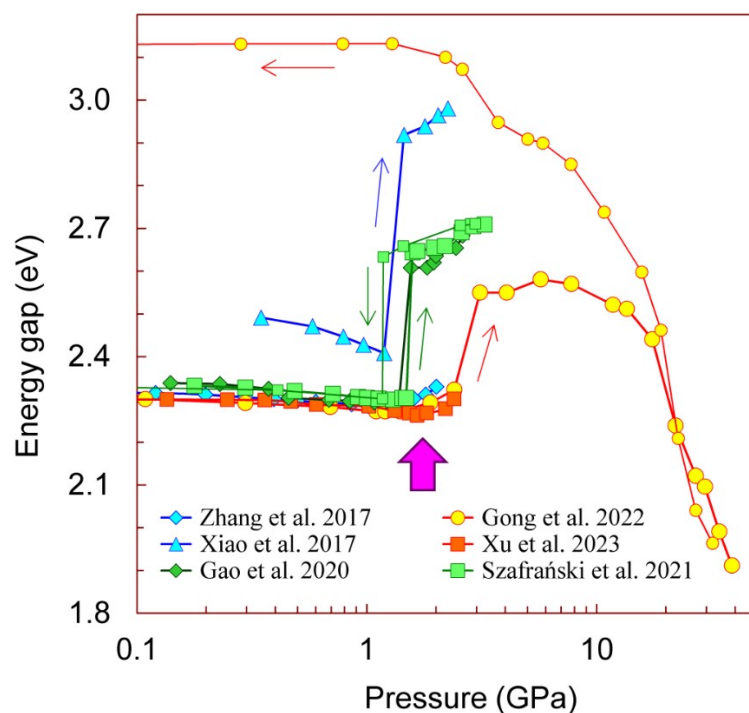


Fig. S1. Pressure dependence of the energy gap of different samples of CsPbBr₃ perovskite at room temperature, taken from the literature [1-6]. Zhang *et al.* - Ref. [1] for a bulk sample in silicone oil medium; Szafranski *et al.* - Ref. [2] for a single-crystal plate in isopropanol medium; Gong *et al.* - Ref. [3] for a single crystal in silicone oil medium; Xu *et al.* - Ref. [4] for a quantum dots in silicone oil medium; Gao *et al.* - Ref. [5] for a nanocrystal in silicone oil medium; Xiao *et al.* - Ref. [6] for a nanocrystal in silicone oil medium. Thin arrows indicate the direction of pressure variation. A bold vertical arrow between 1 and 2 GPa points a phase transition to a disordered phase.

Sample Characterization. The XRD patterns of HPT-CsPbBr₃ were recorded with a Bruker D8 Venture diffractometer with a CMOS PHOTON III detector and an I μ S 3.0 microfocus source (Cu K α radiation, $\lambda = 1.54178$ Å, Montel focusing mirrors) at 298K. Debye diffraction patterns with continuous diffraction arcs were obtained by ϕ -scanning (0.5°-frames, 360°; Fig. S4). For the PXRD patterns (Figs. S2 and S3), to diminish the effect of the preferred orientations, five ϕ -scans for as-is-CsPbBr₃ and HPT-CsPbBr₃ were made at different positions of a goniometer for ω from -240° to 0° [7]. The external standard (Si) correction and integration were performed using the Dioptas program [8].

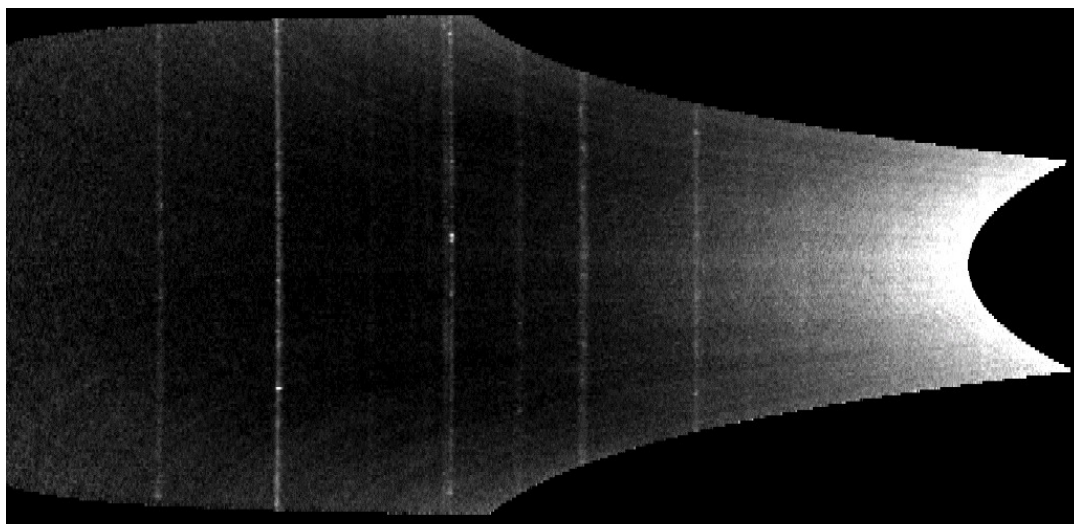


Fig. S2. 2D integration pattern (ϕ -scan 360°) of the HPT-CsPbBr₃ sample.

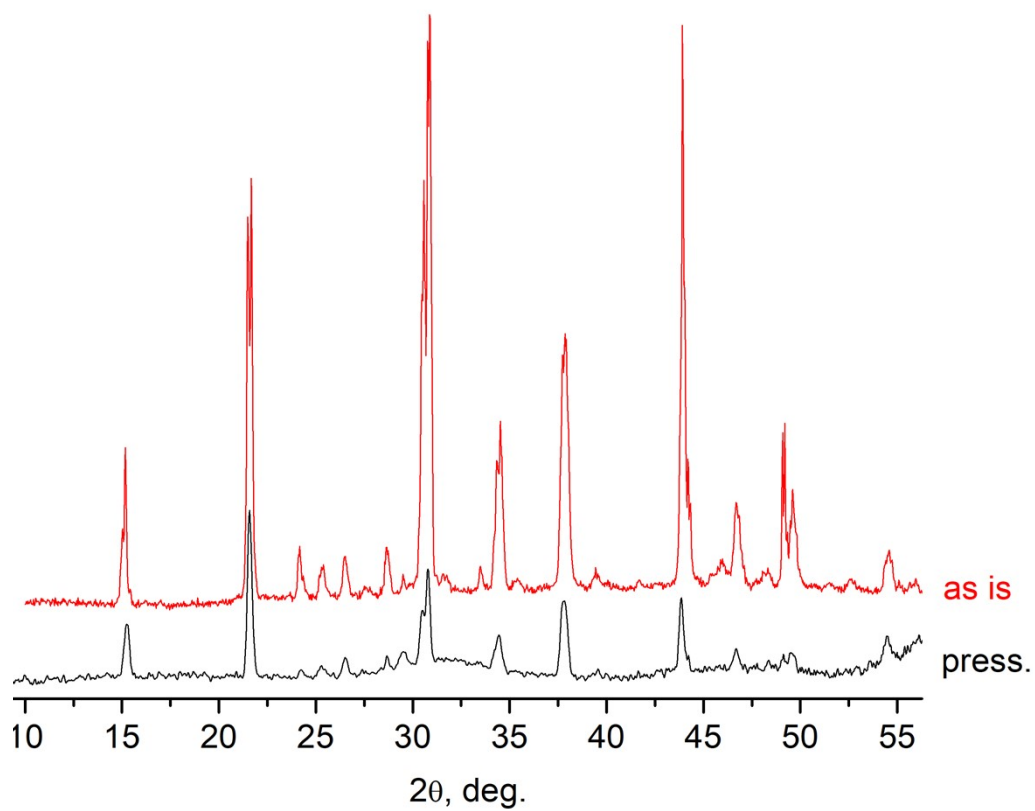


Fig. S3. Experimental powder X-ray diffraction patterns of origin CsPbBr₃ and HPT-CsPbBr₃ samples (Cu K α).

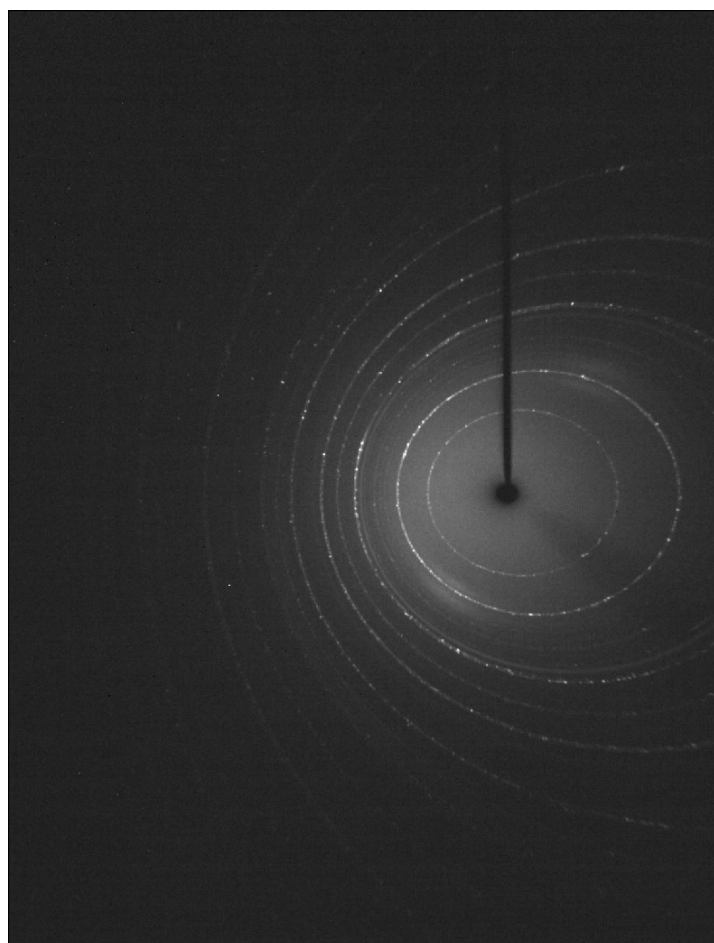


Fig. S4. Debye rings (ϕ -scan of 0.5° -frames) of the HPT-CsPbBr₃ sample.

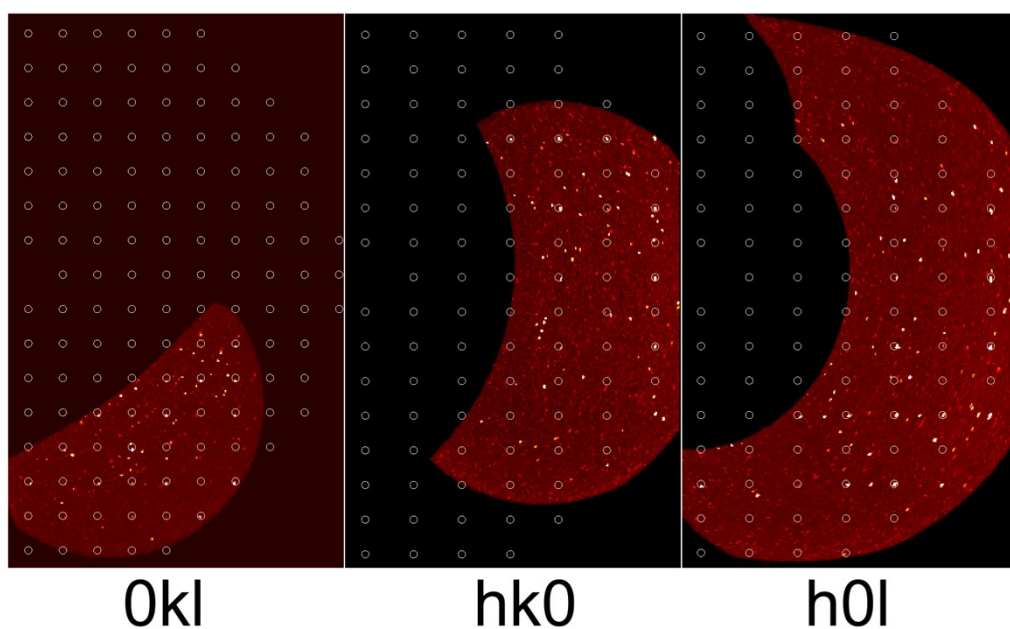


Fig. S5. Reciprocal space reconstructions for the HPT-CsPbBr₃ sample. White circles indicate positions of the reflections for the orthorhombic P lattice, $a = 5.872 \text{ \AA}$, $b = 8.213 \text{ \AA}$, $c = 8.254 \text{ \AA}$, $V = 398.1 \text{ \AA}^3$. Superstructural reflections are unobserved.

References

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